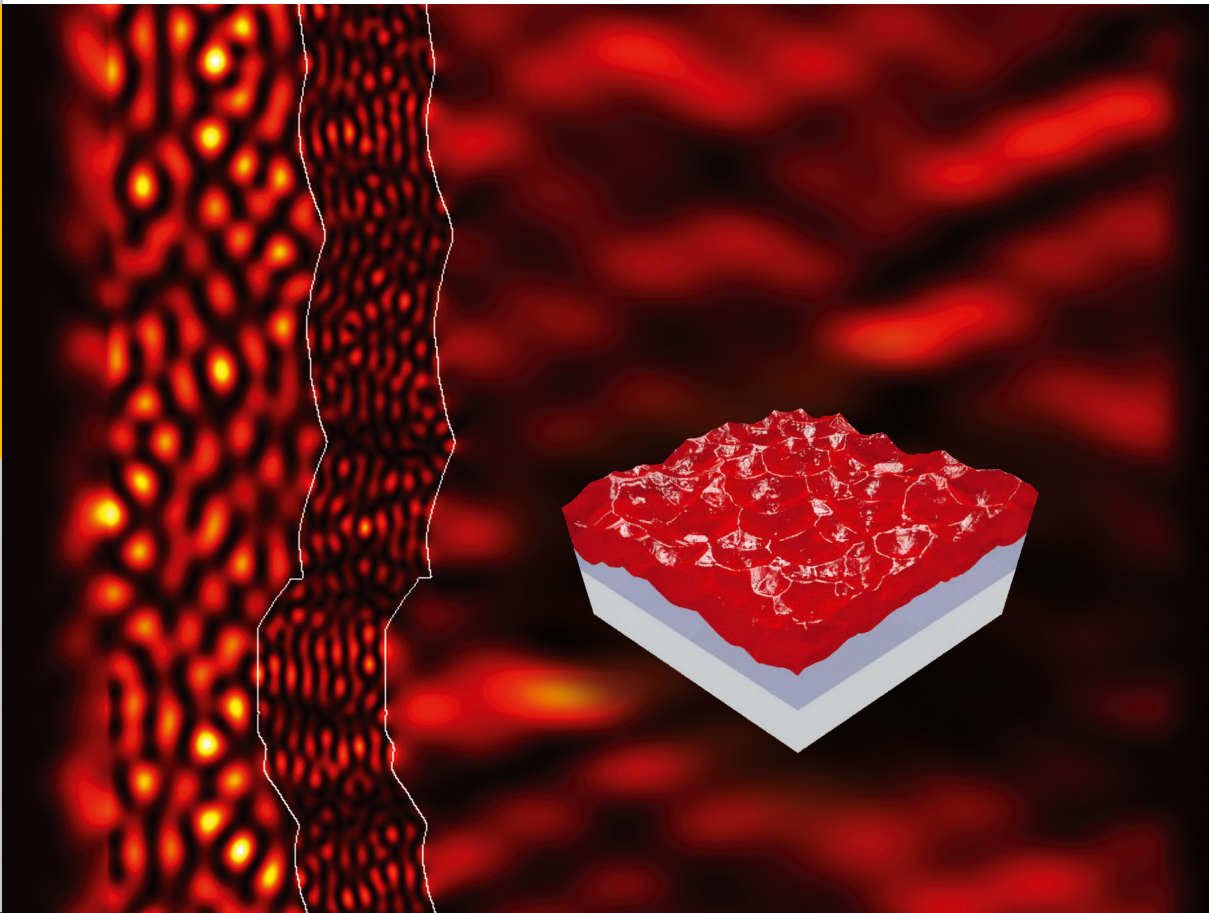


Optical near-field investigations of photonic structures for application in silicon-based thin-film solar cells

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Schriften des Forschungszentrums Jülich
Reihe Energie & Umwelt / Energy & Environment

Band / Volume 299

ISSN 1866-1793

ISBN 978-3-95806-108-8

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**Energie & Umwelt /
Energy & Environment
Band / Volume 299
ISBN 978-3-95806-108-8**

